

Design optimization of polarization engineered III-Nitride tunnel FETs

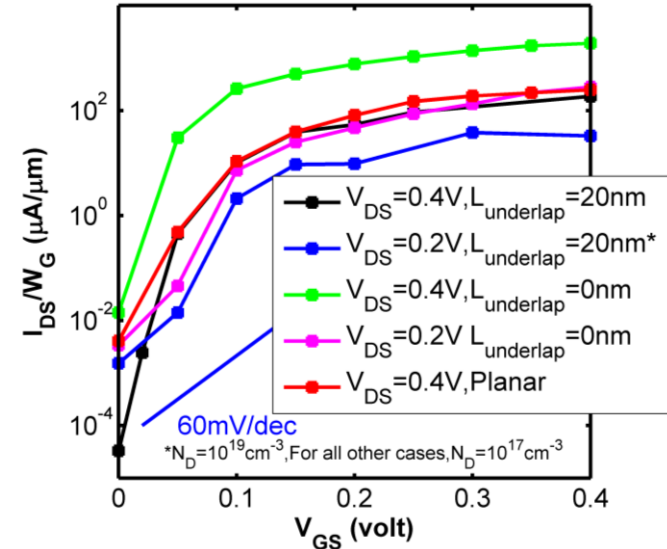
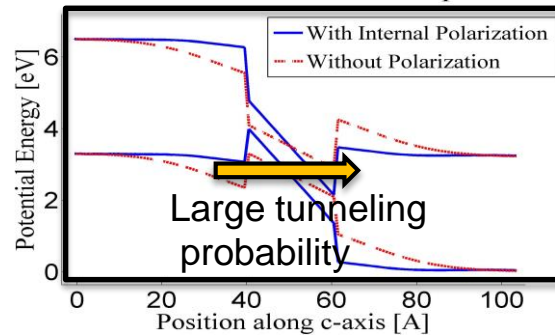
Objective:

- Model optimized TFETs by utilizing polarization induced field in Nitrides (high I_{ON} and low SS at low supply voltage)

Simulation method:

Balistic simulation using Quantum Transmitting Boundary Method (QTBM)

Conduction and Valence Band profile

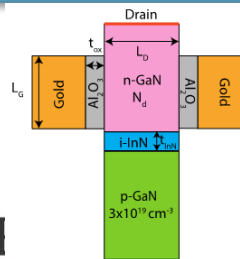


Results:

- Geometry with the best gate control (low Subthreshold Swing, SS) and highest I_{ON} is explored.
- Good I-V characteristics observed even at supply voltage as low as 200mV for L-shaped geometry.

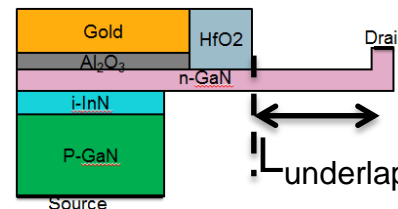
SS: 25mV/dec
 I_{ON} : 247 $\mu A/\mu m$

Sidewall-gate geometry



SS: 12mV/dec
 I_{ON} : 187 $\mu A/\mu m$

L-shaped
 $L_{underlap}$ = 20nm



SS: 15mV/dec
 I_{ON} : 1911 $\mu A/\mu m$

L-shaped
 $L_{underlap}$ = 0nm

